High-density HTS interconnects with ultra-low thermal loss

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Motivation: practical quantum computers would need 1,000's of interconnects

Existing IBM system



Solution: high density superconducting cable With ultra-low thermal loss



² Brookhaven Technology Group

Solution: exfoliated HTS striplies



 By transferring epitaxial HTS layer to a low-loss dielectric we reduce the thermal loss by x100, impossible with Wiedemann-Franz metals
Data transfer from 60-70 K can be efficiently accomplished by off-shelf Si opto-electronics

Advantages of the exfoliated YBCO-Kapton





Smooth surface





Narrow line patterning for high-density striplines



Optimization of laser patterning and compression level

7 W





15 W, optimum power



2.2 copper [20 -1.0 50 100 200 250 300 150 -0.9 -0.6 -0.3 0.0 CTE gap between YBCO and Kapton Strain limits for YBCO

Careful managing of thermal effects level is critical \checkmark



0.3

0.6

0.9

 $200\,\mu m$

30 W

Metallization and contact resistance



✓ $1 \times 10^{-6} \Omega$ per 1 cm length x 1 cm wide contact resistance demonstrated. Tested up to 200 A in LN2

Air-gapped YBCO-on-Kapton microstrip



Insertion loss up to 5.5 GHz, the first air-gapped prototype











f (GHz)

S21

Tested at Brookhaven National Laboratory

Resonances due to gap size variation in the first prototype



Air-gapped microstrip test, in vacuum conduction cooling





Thermal break

Cooling strap



✓ Approx. 3 hours equilibration time



18 K - RT cycling of the air-gapped microstrip



The assembly sustained 5 cycles from 18 K to room temperature
Central line sustained up to 10 mA current at 18 K



Dielectric YBCO-on-Kapton microstrip

Ground plane side, 33 Ω RT

- 0.33 mm thick dielectric, $\varepsilon = 3.2$
- 12 cm long
- Projected 50 Ω impedance at 0.8 mm
- 3 lines 3 mm apart



Signal line side, 0.8 mm wide lines, 500 – 600 Ω RT

Metallization





Copper lead attached



Assembled dielectric YBCO-on-Kapton microstrip

Signal plane side



Assembled microstrips



<complex-block>

Ground plane side



Conduction cooling test of the dielectric microstrip



The assembly sustained 5 cycles from 18 K to room temperature

Central line sustained up to 10 mA current at 18 K







Liquid Nitrogen test



Possibly extra solder in the gap caused high losses > 50 MHz



Successful conduction cooled test: dielectric microstrip



✓ Insertion loss \approx 0.1 dB at 500 MHz at 18 K



Power dependence of the loss



Mechanism of the power dependence needs to be further investigated

Failed dielectric microstrip: residual resistance





Signal line failed probably due to mechanical damage



Future work: quality factor of resonator







Resonator design





The signal line diagnostics





Straight resonator







Summary

- Manufactured air-gapped and dielectric 3-filament microstrips
- Demonstrated superconducting transition in conduction-cooled mode
- Detailed insertion loss measurements up to 500 MHz at 18 K, conduction cooled
- Air-gapped microstrips exhibited high loss > 50 MHz, possibly due to excessive solder in the gap
- Dielectric microstrips demonstrates 0.1 dB at 500 MHz at 18 K

